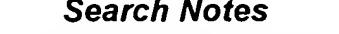


<b>Search Notes</b> 	<b>Application/Control No.</b> 10/020,892	<b>Applicant(s)/Patent under Reexamination</b> TANAKA ET AL.
	<b>Examiner</b> Duyen M. Doan	<b>Art Unit</b> 2143

**SEARCHED**

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner